PCN Nui	N Number: 20240123000.1											F	PCN Date	e:	January 2024	24,
Title: Qualification of CDAT as an additional Assembly site for select devices																
Customer Contact: Change Management Team Dept: Quality Services																
Propose	Proposed 1 st Ship Date: April 22, 2024 Sample requests accepted until: Feb 23, 2024)24							
*Sample requests received after Feb 23, 2024 will not be supported.																
Change Type:																
	☐ Assembly Site ☐ Design ☐ Wafer Bump Material															
	embly Pro				H		ta She				닏				p Process	
	embly Mat		ation		H	_	irt numb	oer ch	an	ge	片		Wafer F			
	:hanical S king/Shipp	•			H		est Site est Proc	ASS			片				Material Process	
	Kirig/ Strip	Jiriy/ La	ibellin	9			PCN D		lc		Ш	l	Waleri	ab	1100633	
Descrip	tion of Cl	hange	:				CITE	Ctur								
	Texas Instruments Incorporated is announcing the qualification of CDAT as an additional Assembly site for the devices listed below. Construction differences are as follows:															
			ι	JTL1/	3		HN	IA		ATX	SZ	(A	SEN)	N) CDAT		
	Mold Compound	ı	SID#CZ0135, SID#CZ0136				SID#4	50176		SID#18015121			12111	11 4222198		
Mount Compound			SID#PZ0037				SID#40	00194		SID#14003361			36111	.11 4226215		
Bond wire composition, diameter			Au, 1.0 mil				Au, 0.8 mil			Au, 0.8 mil			mil	Cu, 0.8 mil		
Reason for Change:																
	ontinuity															
,		act on	Eorn	a Eit	En	nct	ion Ou	ıəlity	or	Doliak	.ili+	· / (nositive	. /	negative	١.
None	iteu iiipi	act on	1 0111	1, 110,	ı u	IICC	ion, qu	ianty	UI	Kenar	,,,,,,	· y (positive	/	ilegative,	<i>)</i> •
	on Envir	onmer	ntal R	ating	S											
															on of this ironmenta	
RoHS			REACH							reen Status				IEC 62474		
No Change		⊠ I	No Change				No Change				☐ No Change					
Changes to product identification resulting from this PCN:																
Assembly Site Assembly Site (22L)		Origin			Assembly Country Co (23L)			ode	е		sembly Cit	ty				
UT	UTL1 NSE THA Bangkok															
UT	UTL3			UT3				T	THA				Bangpakong			
ASEN			ASN				CHN					Suzhou				
Н	NA			HNT	HNT			THA					Ayutthaya			
CDAT			CDA				CHN					Chengdu				

Sample product shipping label (not actual product label)



MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04

PT: 1750 LBL: 5A (L)TO:1750



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812 (P) PEV: (V) 0033317

(P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected:

BQ24392RSER	INA199C1RSWT	INA212BIRSWR	INA214CIRSWR
INA199A1RSWR	INA199C2RSWR	INA212CIRSWR	INA215BIRSWR
INA199A1RSWT	INA199C3RSWR	INA213AIRSWR	INA215CIRSWR
INA199A2RSWR	INA199C3RSWT	INA213AIRSWT	INA216A1RSWR
INA199A3RSWR	INA210AIRSWR	INA213BIRSWR	INA216A1RSWT
INA199B1RSWR	INA210BIRSWR	INA213CIRSWR	INA216A2RSWR
INA199B2RSWR	INA210CIRSWR	INA213CIRSWT	INA216A2RSWT
INA199B3RSWR	INA211BIRSWR	INA214AIRSWR	INA216A3RSWR
INA199C1RSWR	INA211CIRSWR	INA214BIRSWR	INA216A4RSWR



Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Conditions	Qual Device: INA190A1IRSWR	Qual Device: INA190A3IRSWR	Qual Device: INA190A5IRSWR	
PC	Preconditioning	Level 1 - 260C	1/308/0	1/308/0	1/308/0	
SAM	Post Preconditioning SAM	Level 1 - 260C	1/15/0	1/15/0	1/15/0	
UHAST	Unbiased HAST, 110C	264 Hours	1/77/0	1/77/0	1/77/0	
SAM	Post Unbiased HAST SAM	Devices	1/5/0	1/5/0	1/5/0	
BHAST	Biased HAST, 110C	264 Hours	1/77/0	1/77/0	1/77/0	
SAM	Post Biased HAST SAM	Devices	1/5/0	1/5/0	1/5/0	
TC	Temperature Cycle, -55/125C	700 Cycles	1/77/0	1/77/0	1/77/0	
SAM	Post Temperature Cycle SAM	Devices	1/5/0	1/5/0	1/5/0	
HTSL	High Temp Storage Life, 150C	1000 Hours	1/77/0	1/77/0	1/77/0	
HTOL	High Temp Op Life, 125C	1000 Hours	1/77/0	1/77/0	1/77/0	
SD	Solderability, Pb-Free	155C Dry Bake	1/22/0	1/22/0	1/22/0	
MQ	Manufacturability (Assembly)	(per mfg site requirements)	1/PASS	1/PASS	1/PASS	
DSS	Die Shear Strength	Die	1/10/0	1/10/0	1/10/0	
BBS	Ball Bond Shear	Ball Bonds	1/76/0	1/76/0	1/76/0	
WBP	Wire Bond Pull	Wires	1/76/0	1/76/0	1/76/0	
VM	Visual Mechanical Inspection	Devices	1/22/0	1/22/0	1/22/0	
XR	Internal X-ray	Devices	1/5/0	1/5/0	1/5/0	
PD	Physical Dimensions	(per pkg dwg requirements)	1/5/0	1/5/0	1/5/0	
CHAR	Electrical Characterization	Devices	1/30/0	1/30/0	1/30/0	
MSL	Moisture Sensitivity Level	Level 1 - 260C	1/15/0	1/15/0	1/15/0	
YLD	FTY and Bin Summary	Lots	1/PASS	1/PASS	1/PASS	

- Preconditioning was performed for Unbiased HAST, Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable.
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1000 Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours. The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1000 Hours, and 170C/420 Hours.
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles.

Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

Change Number: C2201147, C2303213 TI Qualification ID: R-CHG-2201-048



Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: INA199B3RSWR	Qual Device: INA213AIRSWR	Qual Device: INA214AIRSWR	
PC	Preconditioning	Level 1 - 260C	1/308/0	1/308/0	1/308/0	
SAM	Pre Preconditioning SAM	Devices	1/15/0	1/15/0	1/15/0	
SAM	Post Preconditioning SAM	Devices	1/15/0	1/15/0	1/15/0	
HTOL	High Temp Operating Life, 125C	1000 Hours	1/77/0	1/77/0	1/77/0	
UHAST	Unbiased HAST, 110C	264 Hours	1/77/0	1/77/0	1/77/0	
SAM	Post Unbiased HAST SAM	Devices	1/15/0	1/15/0	1/15/0	
BHAST	Biased HAST, 110C	264 Hours	1/77/0	1/77/0	1/77/0	
SAM	Post Biased HAST SAM	Devices	1/15/0	1/15/0	1/15/0	
TC	Temperature Cycle, -55C/125C	700 Cycles	1/77/0	1/77/0	1/77/0	
SAM	Post Temperature Cycle SAM	Devices	1/15/0	1/15/0	1/15/0	
HTSL	High Temp Storage Life, 150C	1000 Hours	1/77/0	1/77/0	1/77/0	
SAM	Post HT Storage Life SAM	Devices	1/15/0	1/15/0	1/15/0	
SD	Solderability, Pb-Free	155C Dry Bake	1/22/0	1/22/0	1/22/0	
MQ	Manufacturability (Assembly)	(per mfg site requirements)	1/PASS	1/PASS	1/PASS	
DSS	Die Shear Strength	Die	1/10/0	1/10/0	1/10/0	
BBS	Ball Bond Shear	Ball Bonds	1/36/0	1/36/0	1/36/0	
WBP	Wire Bond Pull	Wires	1/36/0	1/36/0	1/36/0	
PD	Physical Dimensions	(per pkg dwg requirements)	1/5/0	1/5/0	1/5/0	
XR	Internal X-Ray	Top side down	1/5/0	1/5/0	1/5/0	
CHAR	Electrical Characterization	Devices	1/30/0	1/30/0	1/30/0	
MSL	Moisture Sensitivity Level	Level 1 - 260C	1/15/0	1/15/0	1/15/0	

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, and Thermal Shock, as applicable

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status: Qualified Pb-Free (SMT) and Green

Change Number: C2207191 TI Qualification ID: R-CHG-2207-065

For questions regarding this notice, e-mails can be sent to Change Management team or your local Field Sales Representative.

IMPORTANT NOTICE AND DISCLAIMER

The following are equivalent Temperature Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

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